

**Notice of References Cited**

Application/Control No.

10/587,440

Applicant(s)/Patent Under  
Reexamination  
STURMER, RAINER

Examiner

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Art Unit

1625

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,312,950	05-1994	Boaz, Neil W.	558/51
*	B	US-5,914,263	06-1999	Buizer et al.	435/280
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	JP 02142495	05-1990	JP	NISHIO ET AL.	A61 K 31/416
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Liu et al. Chirality 2000, 12, 26-29.
	V	Gutman et al. Tetrahedron: Asymmetry (1993), 4(5), 839-44.
	W	Nishio et al. STN ACCESSION NUMBER: 1990:550895 Abstract of JP 02142495.
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.